

Type	Hits	Search Text	DBs	Time Stamp	Comments
1	BRS 6	automat\$3 with test\$3 with factory with information	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/10/14 11:12	
2	BRS 29	automat\$3 with test\$3 with electrical with manufacture\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/10/14 11:11	
3	BRS 8	automat\$3 with test\$3 with electrical with manufacture\$1 and (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:12	
4	BRS 18	automat\$3 with test\$3 with electrical same manufacture\$1 and (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:16	
5	BRS 2	automat\$3 with test\$3 with electrical same manufacture\$1 and (ID or identification\$1 or identifier\$1 or serial) and control\$4 with command\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:19	

Type	Hits	Search Text	DBS	Time Stamp	Comments
6	BRS 39	automat\$3 with test\$3 with electrical and manufacture\$1 and (ID or identification\$1 or identifier\$1 or serial) and control\$4 with command\$1 and (file\$1 or database)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:43	
7	BRS 1	automat\$3 with test\$3 with electrical and manufacture\$1 and correct with (ID or identification\$1 or identifier\$1 or serial) and control\$4 with command\$1 and stored with (file\$1 or database)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:45	
8	BRS 15	automat\$3 with test\$3 with electrical and manufacture\$1 and (ID or identification\$1 or identifier\$1 or serial) and control\$4 with command\$1 and stored with (file\$1 or database)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:48	

Type	Hits	Search Text	DBs	Time Stamp	Comments
9	1	automat\$3 with test\$3 with electrical and manufacture\$1 and (verify\$3 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial) and control\$4 with command\$1 and stored with (file\$1 or database)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:56	
10	5	automat\$3 with test\$3 with electrical and manufacture\$1 and (verify\$3 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:38	
11	1	automat\$3 with test\$3 with instrument\$1 same electrical and manufacture\$1 and (verify\$3 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:40	

Type	Hits	Search Text	DBS	Time Stamp	Comments
12	BRS 2	automat\$3 with test\$3 with instrument\$1 and electrical with voltages\$1 and manufacture\$1 and (verif\$7 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:40	
13	BRS 2	automat\$3 with test\$3 and electrical with voltage\$1 with instrument\$1 and manufacture\$1 and (verif\$7 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:41	
14	BRS 1	automat\$3 with test\$3 and electrical with voltages\$1 and hi-pot with test\$3 with instrument\$1 and manufacture\$1 and (verif\$7 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:41	

Type	Hits	Search Text	DBs	Time Stamp	Comments
		automat\$3 with test\$3 and electrical with voltages\$1 and hi-pot with test\$3 with instrument\$1 and manufacture\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:41	
15	BRS 1	automat\$3 with test\$3 and hi-pot with test\$3 with instrument\$1 and manufacture\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:42	
16	BRS 1	hi-pot with test\$3 with instrument\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:42	
17	BRS 4	hi-pot with test\$3 with instrument\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:42	
18	BRS 1	automat\$3 with test\$3 and electrical with voltages\$1 and (high-potential or (high adj potential) or hi-pot) with test\$3 with instrument\$1 and manufacture\$1 and (verif\$7 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:42	

Type	Hits	Search Text	DBs	Time Stamp	Comments
19	BRS 2	automat\$3 with test\$3 and electrical with voltages\$1 and (high-potential or (high adj potential) or hi-pot) with test\$3 with instrument\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:43	
20	BRS 5	electrical with voltage\$1 and (high-potential or (high adj potential) or hi-pot) with test\$3 with instrument\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:52	
21	BRS 25	"4434489".uref.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:52	
22	BRS 0	"4434489".uref. and electric\$2 with instrument\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:53	
23	BRS 3	"4434489".uref. and electric\$4 and instrument\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:54	

Type	Hits	Search Text	DBS	Time Stamp	Comments
24	BRS 162	automat\$3 with test\$3 same electrical and manufacture\$1 and (ID or identification\$1 or identifier\$1 or serial) with number\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:54	
25	BRS 8	automat\$3 with test\$3 same electrical and manufacture\$1 and (verif\$7 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial) with number\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:00	
26	BRS 87	automat\$3 with test\$3 and electrical and manufacture\$1 and (verif\$7 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial) with number\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:16	

Type	Hits	Search Text	DBS	Time Stamp	Comments
27	BRS 63	automat\$3 with test\$3 and electrical and manufacture\$1 and (verif\$7 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial) with number\$1 and read\$3 with (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:16	
28	BRS 12	automat\$3 with test\$3 and electrical and manufacture\$1 and (verif\$7 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial) with number\$1 and read\$3 with (ID or identification\$1 or identifier\$1 or serial) with (file\$1 or database\$1 or folder\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:17	

Type	Hits	Search Text	DBs	Time Stamp	Comments
29	BRS 0	automat\$3 with test\$3 and voltage\$1 with tolrance\$1 and test\$3 with (cod\$3 or program\$1 or software) with instrument\$1 with port\$1 with operating	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:45	
30	BRS 1	automat\$3 with test\$3 and voltage\$1 with tolerance\$1 and test\$3 with (cod\$3 or program\$1 or software) with instrument\$1 with port\$1 with operating	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:46	
31	BRS 1	automat\$3 with test\$3 and test\$3 with (cod\$3 or program\$1 or software) with instrument\$1 with port\$1 with operating	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:46	
32	BRS 29	automat\$3 with test\$3 with electrical with manufacture\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:11	
33	BRS 8	automat\$3 with test\$3 with electrical with manufacture\$1 and (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:12	

Type	Hits	Search Text	DBs	Time Stamp	Comments
34	BRS 64	automat\$3 with test\$3 with factor\$3 with (information\$1 or data)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/10/14 11:13	
35	BRS 0	automat\$3 with test\$3 with voltage\$1 with tolerance with factor\$3 with (information\$1 or data)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/10/14 11:15	
36	BRS 3	automat\$3 with test\$3 with voltage\$1 with factor\$3 with (information\$1 or data)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/10/14 11:15	
37	BRS 18	automat\$3 with test\$3 with electrical same manufacturer\$1 and (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:17	
38	BRS 50	automat\$3 with test\$3 with electrical same manufacturer\$3 and (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:17	
39	BRS 31	automat\$3 with test\$3 with electrical with manufacturer\$3 and (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:17	

Type	Hits	Search Text	DBs	Time Stamp	Comments
40	BRS 1	automat\$3 with test\$3 with electrical with manufactur\$3 and verif\$3 with (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:17	
41	BRS 2	automat\$3 with test\$3 with electrical same manufacture\$1 and (ID or identification\$1 or identifier\$1 or serial) and control\$4 with command\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:32	
42	IS&R 2	("5081598") .PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:33	
43	IS&R 2	("5151652") .PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:33	

Type	Hits	Search Text	DBS	Time Stamp	Comments
44	BRS 40	automat\$3 with test\$3 with electrical and manufacture\$1 and (ID or identification\$1 or identifier\$1 or serial) and control\$4 with command\$1 and (file\$1 or database)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:43	
45	BRS 1	automat\$3 with test\$3 with electrical and manufacture\$1 and correct with (ID or identification\$1 or identifier\$1 or serial) and control\$4 with command\$1 and stored with (file\$1 or database)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:45	
46	BRS 15	automat\$3 with test\$3 with electrical and manufacture\$1 and (ID or identification\$1 or identifier\$1 or serial) and control\$4 with command\$1 and stored with (file\$1 or database)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:53	

Type	Hits	Search Text	DBs	Time Stamp	Comments
47	BRS 37	industrial with protocol and bit with stream	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/10/14 11:54	
48	BRS 0	industrial with protocol and bit with stream and xml with encoded	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/10/14 11:54	
49	BRS 1	industrial with protocol and bit with stream same encoded	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/10/14 11:54	
50	BRS 2398	protocol and bit\$1 with stream\$1 same encoded	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/10/14 11:55	
51	BRS 1524	protocol and bit\$1 with stream\$1 with encoded	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/10/14 11:55	
52	BRS 0	protocol and bit\$1 with stream\$1 with encoded with xml	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/10/14 11:55	

Type	Hits	Search Text	DBs	Time Stamp	Comments
53	BRS 0	protocol and bit\$1 with stream\$1 with encoded same xml	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/10/14 11:55	
54	BRS 13	protocol and bit\$1 with stream\$1 with encoded with payload\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/10/14 11:58	
55	BRS 1	automat\$3 with test\$3 with electrical and manufacture\$1 and (verify\$3 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial) and control\$4 with command\$1 and stored with (file\$1 or database)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 11:56	
56	BRS 1	protocol and bit\$1 with stream\$1 with encoded same payload\$3 and xml	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/10/14 11:58	
57	BRS 2	protocol and bit\$1 with stream\$1 with encoded and payload\$3 with xml	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/10/14 11:59	

Type	Hits	Search Text	DBs	Time Stamp	Comments
58	BRS 0	protocol and binary with bits\$1 with stream\$1 with encoded and payload\$3 with xml	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/10/14 12:00	
59	BRS 5	protocol and binary with bit\$1 with stream\$1 with encoded and payload\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2005/10/14 12:00	
60	BRS 7	automat\$3 with test\$3 with electrical and manufacture\$1 and (verify\$3 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:38	
61	BRS 1	automat\$3 with test\$3 with instrument\$1 same electrical and manufacture\$1 and (verify\$3 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:40	

Type	Hits	Search Text	DBs	Time Stamp	Comments
62	BRS 2	automat\$3 with test\$3 with instrument\$1 and electrical with voltage\$1 and manufacture\$1 and (verif\$7 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:40	
63	BRS 2	automat\$3 with test\$3 and electrical with voltage\$1 with instrument\$1 and manufacture\$1 and (verif\$7 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:41	
64	BRS 1	automat\$3 with test\$3 and electrical with voltage\$1 and hi-pot with test\$3 with instrument\$1 and manufacture\$1 and (verif\$7 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:41	

Type	Hits	Search Text	DBs	Time Stamp	Comments
65	BRS 1	automat\$3 with test\$3 and electrical with voltages\$1 and hi-pot with test\$3 with instrument\$1 and manufacture\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:41	
66	BRS 1	automat\$3 with test\$3 and hi-pot with test\$3 with instrument\$1 and manufacture\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:42	
67	BRS 4	hi-pot with test\$3 with instrument\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:48	
68	BRS 1	automat\$3 with test\$3 and electrical with voltage\$1 and (high-potential or (high adj potential) or hi-pot) with test\$3 with instrument\$1 and manufacture\$1 and (verif\$7 or validate\$3) with (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:42	

Type	Hits	Search Text	DBS	Time Stamp	Comments
69	BRS 2	automat\$3 with test\$3 and electrical with voltages\$1 and (high-potential or (high adj potential) or hi-pot) with test\$3 with instrument\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:43	
70	BRS 5	electrical with voltages\$1 and (high-potential or (high adj potential) or hi-pot) with test\$3 with instrument\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:52	
71	BRS 25	"4434489".uref.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:52	
72	BRS 0	"4434489".uref. and electric\$2 with instrument\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:53	
73	BRS 3	"4434489".uref. and electric\$4 and instrument\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:54	

Type	Hits	Search Text	DBs	Time Stamp	Comments
74	BRS 176	automat\$3 with test\$3 same electrical and manufacture\$1 and (ID or identification\$1 or identifier\$1 or serial) with number\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 13:54	
75	BRS 8	automat\$3 with test\$3 same electrical and manufacture\$1 and (verif\$7 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial) with number\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:00	
76	BRS 91	automat\$3 with test\$3 and electrical and manufacture\$1 and (verif\$7 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial) with number\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:16	

Type	Hits	Search Text	DBS	Time Stamp	Comments
77	BRS 67	automat\$3 with test\$3 and electrical and manufacture\$1 and (verif\$7 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial) with number\$1 and read\$3 with (ID or identification\$1 or identifier\$1 or serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:16	
78	BRS 14	automat\$3 with test\$3 and electrical and manufacture\$1 and (verif\$7 or validat\$3) with (ID or identification\$1 or identifier\$1 or serial) with number\$1 and read\$3 with (ID or identification\$1 or identifier\$1 or serial) with (file\$1 or database\$1 or folder\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:17	

Type	Hits	Search Text	DBs	Time Stamp	Comments
		automat\$3 with test\$3 and voltage\$1 with tolrance\$1 and test\$3 with (cod\$3 or program\$1 or software) with instrument\$1 with port\$1 with operating	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:45	
79	0	automat\$3 with test\$3 and voltage\$1 with tolerance\$1 and test\$3 with (cod\$3 or program\$1 or software) with instrument\$1 with port\$1 with operating	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:46	
80	1	automat\$3 with test\$3 and test\$3 with (cod\$3 or program\$1 or software) with instrument\$1 with port\$1 with operating	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:46	
81	1	automat\$3 with test\$3 and test\$3 with (cod\$3 or program\$1 or software) with instrument\$1 with port\$1 with operating	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:46	
82	7	(high-potential or high adj potential or hi-pot) with test\$3 with instrument\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:49	
83	2	(high-potential or high adj potential or hi-pot) with test\$3 with instrument\$1 and control\$4 with command\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:49	

Type	Hits	Search Text	DBS	Time Stamp	Comments
84	BRS 12320	702/57, 64, 65, 119, 122, 123.c ccls. or 324/73.1, 511, 536, 538, 539, 5 40, 541, 544, 551.ccls. or 714/46, 47, 48, 49, 50, 51, 719, 720, 724.ccls.) and tests\$3 with voltage\$1 with tolerance with tlectrical with operation with system\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 14:59	
85	BRS 0	(702/57, 64, 65, 119, 122, 123. ccls. or 324/73.1, 511, 536, 538, 539, 5 40, 541, 544, 551.ccls. or 714/46, 47, 48, 49, 50, 51, 719, 720, 724.ccls.) and tests\$3 with voltage\$1 with tolerance with electrical with operation with system\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 15:00	
86	BRS 0			2005/10/14 15:01	

Type	Hits	Search Text	DBs	Time Stamp	Comments
87	BRS 0	(702/57, 64, 65, 119, 122, 123. cc1s. or 324/73.1, 511, 536, 538, 539, 540, 541, 544, 551.cc1s. or 714/46, 47, 48, 49, 50, 51, 719, 720, 724.cc1s.) and test\$3 with voltage\$1 with tolerance with electrical with operat\$3 with system\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 15:01	
88	BRS 2	test\$3 with voltage\$1 with tolerance with electrical with operat\$3 with system\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 15:01	
89	BRS 10	(702/57, 64, 65, 119, 122, 123. cc1s. or 324/73.1, 511, 536, 538, 539, 540, 541, 544, 551.cc1s. or 714/46, 47, 48, 49, 50, 51, 719, 720, 724.cc1s.) and test\$3 with voltage\$1 with electrical with operat\$3 with system\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 15:02	

Type	Hits	Search Text	DBS	Time Stamp	Comments
		(702/57,64,65,119,122,123. cc1s. or 324/73.1,511,536,538,539,5 40,541,544,551.cc1s. or 714/46,47,48,49,50,51,719, 720,724.cc1s.) and test\$3 with voltage\$1 with electrical same operat\$3 with system\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 15:02	
91	BRS 3	(702/57,64,65,119,122,123. cc1s. or 324/73.1,511,536,538,539,5 40,541,544,551.cc1s. or 714/46,47,48,49,50,51,719, 720,724.cc1s.) and automat\$6 with test\$3 with voltage\$1 with electrical and operat\$3 with system\$1 (702/57,64,65,119,122,123. cc1s. or 324/73.1,511,536,538,539,5 40,541,544,551.cc1s. or 714/46,47,48,49,50,51,719, 720,724.cc1s.) and test\$3 with voltage\$1 with electrical and operat\$3 with system\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/10/14 15:02	
92	BRS 119			2005/10/14 15:05	

Type	Hits	Search Text	DBs	Time Stamp	Comments
93	BRS 17	(702/57, 64, 65, 119, 122, 123. cc1s. or 324/73.1, 511, 536, 538, 539, 5 40, 541, 544, 551.cc1s. or 714/46, 47, 48, 49, 50, 51, 719, 720, 724.cc1s.) and test\$3 with voltages\$1 with electrical and operat\$3 with system\$1	US-PGPUB	2005/10/14 15:10	
94	BRS 6	(702/57, 64, 65, 119, 122, 123. cc1s. or 324/73.1, 511, 536, 538, 539, 5 40, 541, 544, 551.cc1s. or 714/46, 47, 48, 49, 50, 51, 719, 720, 724.cc1s.) and test\$3 with voltages\$1 with electrical and operat\$3 with system\$1 and (communication\$1 or connect\$3) with (wire\$1 or port\$1)	US-PGPUB	2005/10/14 15:13	

Type	Hits	Search Text	DBS	Time Stamp	Comments
95	BRS 0	(702/57, 64, 65, 119, 122, 123. cc1s. or 324/73.1, 511, 536, 538, 539, 5 40, 541, 544, 551.cc1s. or 714/46, 47, 48, 49, 50, 51, 719, 720, 724.cc1s.) and test\$3 with voltage\$1 with electrical and operat\$3 with system\$1 and (communication\$1 or connect\$3) with (wire\$1 or port\$1) and serial with number	US-PGPUB	2005/10/14 15:13	
96	BRS 0	test\$3 with voltage\$1 with electrical and operat\$3 with system\$1 and (communication\$1 or connect\$3) with (wire\$1 or port\$1) and serial with number	US-PGPUB	2005/10/14 15:13	

Retrieval 1 Classif	Current XRef	Current OR	Title	Page s	Issue Date	Document ID	U 1
714/724	714/724	438/14	Fabrication method of semiconductor integrated circuit device	35	20050714	US 2005015346	1
702/119	702/119	702/119	Dynamically adaptable semiconductor parametric testing	37	20050127	US 2005002127	2
324/511	324/511	324/511	Traction motor fault detection system	18	20041118	US 2004022752	3
702/64	702/64	702/64	Method of analyzing the time-varying electrical response of a stimulated target substance	1	20040701	US 2004012808	4
714/724	714/724	714/724	Enabling multiple testing devices	1	20040624	US 2004012319	5
702/119	702/119	702/119	Dynamically adaptable semiconductor parametric testing	1	20031113	US 2003021252	6
702/123	702/123	702/123	Electronic test program with test triggered interactive displays	1	20030925	US 2003018207	7

U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif 1
	X	US 2003016713	20030904		Plausibility checking of voltage transformers in substations	702/64		702/64
9	X	US 2003016061	20030828		Electric arc synthesis for arc detector testing and method for arc testing	324/536		324/536
10	X	US 2003007916	20030424		Test executive system with progress window	714/46		714/46
11	X	US 2003006730	20030410		Motor terminal fixture	324/538		324/538
12	X	US 2003004087	20030227		Systems and methods for monitoring and storing performance and maintenance data related to an electrical component	702/57		702/57
13	X	US 2003002834	20030206		Intelligent measurement modular semiconductor parametric test system	702/122		702/122

U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
		US 2002017392	20021121		System for testing of intelligent electronic devices with digital communications	702/122		702/122
14	X	US 2002007337	20020613		Testing system for evaluating integrated circuits, a testing system, and a method for testing an integrated circuit	714/724	714/734; 714/765	714/724
15	X	US 2002004994	20020425		Method and apparatus for properly disabling high current parts in a parallel test environment	714/724		
16	X	US 2001002754	20011004		Automated system for estimating ring oscillator reliability and testing AC response and method of operation thereof	714/724	324/763	714/724
17	X	US 2001002754	20011004					

	U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
1			US 2005015346	20050714	35	Fabrication method of semiconductor integrated circuit device	438/14	714/724	714/724
2	X		US 2005002127	20050127	37	Dynamically adaptable semiconductor parametric testing	702/119		702/119
3	X		US 2004022752	20041118		Traction motor fault detection system	324/511		324/511
4	X		US 2004012808	20040701		Method of analyzing the time-varying electrical response of a stimulated target substance	702/64		702/64
5	X		US 2004012319	20040624		Enabling multiple testing devices	714/724		714/724
6	X		US 2003021252	20031113		Dynamically adaptable semiconductor parametric testing	702/119		702/119
7	X		US 2003018207	20030925		Electronic test program with test triggered interactive displays	702/123		702/123

U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
		US 2002017392	20021121		System for testing of intelligent electronic devices with digital communications	702/122		702/122
14	X	US 2002007337	20020613		Testing system for evaluating integrated circuits, a testing system, and a method for testing an integrated circuit	714/734; 714/765	714/724	714/724
15	X	US 2002004994	20020425		Method and apparatus for properly disabling high current parts in a parallel test environment	714/724		714/724
16	X	US 2001002754	20011004		Automated system for estimating ring oscillator reliability and testing AC response and method of operation thereof	714/724	324/763	714/724
17	X	US 6930490	20050816	B2	Traction motor fault detection system	324/511	318/490; 324/522	324/511
18	X							

U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
					Method and circuits for testing high speed devices using low speed ATE testers	702/75	324/511; 324/537; 702/117	324/511
19	X	US B1	6904375	20050607	Method and device for testing a telecommunication cable	324/523	324/522; 324/551	324/551
20	X	US B2	6825670	20041130	Electronic test program with test triggered interactive displays	702/123	714/46	702/123; 714/46
21	X	US B2	6807506	20041019	Plausibility checking of voltage transformers in substations	702/64	324/512; 324/522; 324/537; 324/546; 324/547; 324/772; 702/58; 702/59	702/64
22	X	US B2	6807495	20041019	System for testing of intelligent electronic devices with digital communications	702/122	702/120; 702/57	702/122; 702/57
23	X	US B2	6795789	20040921				

U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
	X	US B2	6795782	20040921	Battery test module	702/63	702/121; 702/188; 702/64; 702/65	
24	X	US B2	6778913	20040817	Multiple model systems and methods for testing electrochemical systems	702/30	702/57	702/57
25	X	US B2	6772380	20040803	Smart tester and method for testing a bus connector	714/724	324/539	324/539; 714/724
26	X	US B1	6737978	20040518	Voltage testing apparatus for electrical railways	340/660	324/539; 324/543; 340/662; 340/663; 340/691.6 ; 340/692	324/539
27	X	US B1						

U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
					Microsystems integrated testing and characterization system and method	702/117	702/115; 702/57; 702/64; 714/735; 714/742; 73/1.41; 73/1.45	
28	X	US B1 6708132	20040316		Method and arrangement for load testing electrical systems of a motor vehicle	324/511	324/501; 73/117.1; 324/511	700/303; 700/302; 324/765; 324/751; 324/243;
29	X	US B2 6690174	20040210			73/865.6		

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			Processing system for a wiring harness, a method for testing an electrical connection of a wiring harness, computer-readable storage medium and a wire connection assisting system	702/118; 702/119; 702/121; 702/122; 702/123	702/117	US 6687639 B2 20040203 32	30 X
			Easy to program automatic test equipment	714/724	702/119	US 6681351 B1 20040120	31 X
			Testing system for evaluating integrated circuits, a testing system, and a method for testing an integrated circuit	714/724	324/763; 714/734	US 6640323 B2 20031028	32 X
			Automatic test equipment methods and apparatus for interfacing with an external device	714/725	714/724	US 6622272 B1 20030916	33 X

Retrieva 1	Current XRef Classif	Current OR	Title	Issue Date	Document ID	U 1
Page s						
34	X	324/73.1	Microelectronic fabrication electrical test apparatus and method providing enhanced electrical test accuracy	US 6590408 B1	20030708	
35	X	324/96; 714/724	Optically driven driver, optical output type voltage sensor, and IC testing equipment using these devices	US 6586953 B1	20030701	
36	X	324/378; 324/538; 324/538	Motor terminal fixture	US 6577131 B2	20030610	
37	X	702/108; 702/117; 702/182; 702/57; 702/81	Battery testing and classification	US 6526361 B1	20030225	
38	X	702/118; 716/11; 716/12	Method for operating a test system	US 6505137 B1	20030107	

U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
39	X	US B1	6498495 20021224		Method and apparatus for testing fuel gas control systems for gas fired appliances	324/546	137/66; 324/514; 324/73.1	
40	X	US B2	6484279 20021119		Testing system for evaluating integrated circuits, a testing system, and a method for testing an integrated circuit	714/724	324/763; 714/734	714/724
41	X	US B1	6349396 20020219		Testing system for evaluating integrated circuits, a burn-in testing system, and a method for testing an integrated circuit	714/724	324/765; 714/734	714/724
42	X	US B1	6327686 20011204		Method for analyzing manufacturing test pattern coverage of critical delay circuit paths	714/738	714/724	714/724

U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif 1
					Apparatus and method for detecting conduit chafing	324/541	324/525; 324/557; 324/720; 324/96; 361/103;	
43	X	US 6265880 B1	20010724		Method and apparatus for determining short circuit conditions using a gang probe circuit tester	324/73.1	324/540; 324/66	324/540; 324/73.1
44	X	US 6201383 B1	20010313		Testing system for evaluating integrated circuits, a burn-in testing system, and a method for testing an integrated circuit	714/724	324/765; 714/734	714/724
45	X	US 6189120 B1	20010213		Very low frequency high voltage sinusoidal electrical testing method, systems and apparatus	324/548	324/511; 324/555	324/511
46	X	US 6169406 B1	20010102	65				

	U 1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
47	X	US A 6119255	20000912		Testing system for evaluating integrated circuits, a burn-in testing system, and a method for testing an integrated circuit	714/724	324/765; 714/734	714/724
48	X	US A 6112159	20000829 27		Robust electrical utility meter	702/61	324/107; 324/140R; 324/142; 324/74; 324/76.77	702/64; 702/65
49	X	US A 6055653	20000425		Method and apparatus for testing gang memory modules	714/718	365/200; 365/201; 714/717; 714/719	714/719
50	X	US A 6051980	20000418		Pulse width modulation simulator for testing insulating materials	324/544	324/551; 324/703	324/544; 324/551

U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
		US 6025708	20000215		System for verifying signal voltage level accuracy on a digital testing device	324/158.1	324/73.1	324/73.1
51	X	US A			Current-leakage tester	324/511	324/508; 324/510;	324/511
52	X	US A	6011398	20000104 25	Apparatus for technical diagnosis of errors in a medical/dental apparatus	700/81	600/526; 702/183; 714/724;	714/724
53	X	US A	5812397	19980922	Methods, apparatus and computer program products for synthesizing integrated circuits with electrostatic discharge capability and connecting ground rules faults therein	716/5	702/170; 702/57; 702/65; 703/18	
54	X	US A	5796638	19980818	Process for checking the efficiency of an electric power station component	324/551		324/551
55	X	US A	5773982	19980630				

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					Apparatus for testing the line continuity of telephone switch equipment	379/22.07 ; 379/25; 379/29.05 ; 379/30	324/539; 324/66; 379/21; 379/22.03	324/539
56	X	US 5764725 A	19980609		Method of manufacture of an interconnect stress test coupon	29/852	324/73.1; 324/760	324/73.1
57	X	US 5701667 A	19971230		Automated system, and corresponding method, for determining average optical output power of electro-optic modules	398/23	398/38; 702/119	702/119
58	X	US 5652668 A	19970729		Pulse width modulation simulator for testing insulating materials	324/551	324/541; 324/544; 324/557	324/541; 324/544; 324/551
59	X	US 5648725 A	19970715					

U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
					Automated system, and corresponding method, for measuring transmitter data-dependent jitter of electro-optic modules	398/32	398/33; 702/119	
60	X	US 5644417 A	19970701		Automated system, and corresponding method, for measuring transmitter rise and fall times of electro-optic modules	398/182	398/25; 702/119	
61	X	US 5612809 A	19970318		System using induced current for contactless testing of wiring networks	324/751	324/501; 324/538	
62	X	US 5612626 A	19970318		Automated system and corresponding method for testing electro-optic modules	702/122	398/23; 398/24	702/122
63	X	US 5598360 A	19970128					

U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
64	X	US 5596587 A	19970121		Method and apparatus for preparing in-circuit test vectors	714/739	702/123	702/123
65	X	US 5579145 A	19961126		Automated system and corresponding method for measuring receiver time delay of electro-optic modules	398/9	356/73.1; 398/23; 398/24; 702/119	702/119
66	X	US 5576980 A	19961119		Serializer circuit for loading and shifting out digitized analog signals	702/119	341/100; 341/101; 714/712	702/119
67	X	US 5576877 A	19961119	22	Automated system, and corresponding method, for measuring receiver signal detect threshold values of electro-optic modules	398/9	398/23; 398/24; 702/119	702/119

U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
		US 5537044 A	19960716		Surge voltage generator for pulsing grounded and ungrounded electrical equipment	324/511	307/107; 324/510; 324/546	324/511
68	X	US 5537030 A	19960716		Voltage regulator test set for the power distribution industry	324/158.1	324/73.1; 324/771; 324/772	324/73.1
69	X	US 5471136 A	19951128		Test system for calculating the propagation delays in signal paths leading to a plurality of pins associated with a circuit	324/158.1	324/73.1	324/73.1
70	X	US 5451885 A	19950919		Interconnect stress test coupon	324/760	324/537; 324/538; 324/73.1	324/538; 324/73.1
71	X	US 5444390 A	19950822		Means and method for sequentially testing electrical components	324/770	324/537; 324/73.1; 324/767; 714/718; 714/720	324/73.1; 714/720
72	X							

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73	X	US A 5436569	19950725		Electronic component testing oven	324/760 ;	324/158.1 ; 324/73.1	324/73.1
74	X	US A 5371457	19941206		Method and apparatus to test for current in an integrated circuit	324/158.1	324/73.1	324/73.1
75	X	US A 5365177	19941115		Apparatus for measurement of high frequency corona discharges in electrical components	324/547	324/548; 324/551	324/551
76	X	US A 5363047	19941108		Portable ground fault detector	324/510	324/509; 324/551; 340/650; 361/31	324/551
77	X	US A 5325068	19940628		Test system for measurements of insulation resistance	324/713	324/73.1	324/73.1
78	X	US A 5221905	19930622		Test system with reduced test contact interface resistance	324/713	324/538; 324/754	324/538

	U 1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval 1 Classif
	X	US 5220285 A	19930615		System for testing the electrical continuity and insulation of the electrical conductors of a portion of wiring	324/540	324/158.1 ; 324/66	324/540
80	X	US 5194817 A	19930316		Apparatus and method for testing insulation using a pulsed resonant power supply	324/544	324/652	324/544
81	X	US 5150059 A	19920922		Method and apparatus for testing the condition of insulating system	324/551	324/546	324/551
82	X	US 5127011 A	19920630		Per-pin integrated circuit test system having n-bit interface	714/740	714/724	714/724
83	X	US 4965800 A	19901023		Digital signal fault detector	714/724	714/709	714/724
84	X	US 4931742 A	19900605		Self-protecting power bus testing system	324/541		324/541

U	1	Document ID	Issue Date	Page S	Title	Current OR	Current XRef	Retrieval Classif 1
		US 4922183 A	19900501		Methods, systems and apparatus for detecting changes in variables	324/694	324/522; 324/539	324/539
85	X	US 4907230 A	19900306		Apparatus and method for testing printed circuit boards and their components	714/724	706/916; 714/26; 714/32; 714/46	714/46; 714/724
86	X	US 4897606 A	19900130		Method and apparatus for undesired ground path detection in a single-point grounded electrical system	324/509	324/510; 324/511; 340/649	324/511
87	X	US 4896101 A	19900123		Method for monitoring, recording, and evaluating valve operating trends	324/73.1	376/245; 73/168; 73/593	324/73.1
88	X	US 4868505 A	19890919		High voltage impulse wave generator for testing equipment	324/511	307/107; 324/510; 324/546	324/511
89	X	US 4862067 A	19890829		Method and apparatus for in-circuit testing of electronic devices	324/73.1		324/73.1
90	X							

U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
91	X	US A 4857833	19890815		Diagnosis of faults on circuit board	324/512	324/522; 702/118; 702/59; 702/64; 706/916	702/64
92	X	US A 4812996	19890314		Signal viewing instrumentation control system	702/123	324/76.24 ; 345/440; 345/440.1 ; 345/661; 715/808; 715/970	702/123
93	X	US A 4810972	19890307		Automatic short circuit tester control device	324/541	324/509; 324/551; 340/650	324/541; 324/551
94	X	US A 4764925	19880816		Method and apparatus for testing integrated circuits	714/743	324/73.1	324/73.1

U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
					Electro-luminescent automatic testing apparatus and method for ceramic substrates, printed circuit boards and like items with background illumination suppression	324/459	324/501; 324/537; 324/539	
95	X	US 4764719 A	19880816					
96	X	US 4757263 A	19880712		Insulation power factor alarm monitor	324/552	324/126; 702/60; 702/65; 702/81	
97	X	US 4698785 A	19871006		Method and apparatus for detecting control system data processing errors	714/38	701/14; 714/32; 714/46; 714/735	
98	X	US 4680761 A	19870714		Self diagnostic Cyclic Analysis Testing System (CATS) for LSI/VLSI	714/724	714/733; 714/736	714/724
99	X	US 4629976 A	19861216		Method and circuit for evaluating an analog voltage	324/72.5	324/133; 324/551	324/551

U	1	Document ID	Issue Date	Page S	Title	Current OR	Current XRef	Retrieval Classif
		US 4606025 A	19860812		Automatically testing a plurality of memory arrays on selected memory array testers	714/718	324/73.1; 714/721	324/73.1
100	X	US 4578767 A	19860325		X-ray system tester	702/64	378/109; 378/110; 378/111; 378/112; 378/207	702/64
101	X	US 4551671 A	19851105		Terminal disconnect and media wire fault detect mechanism	324/539	324/523	324/539
102	X	US 4543523 A	19850924		Test terminal for use in an electric power transmission system	324/552	324/538	324/538
103	X	US 4402055 A	19830830		Automatic test system utilizing interchangeable test devices	702/121	324/73.1; 714/26; 714/724	324/73.1
104	X	US 4402055 A	19830830					

U	1	Document ID	Issue Date	Page S	Title	Current OR	Current XRef	Retrieval Classif 1
					Apparatus for testing multiconductor cables and having transition circuit means for extending its capability			
105	X	US 4399400 A	19830816		Switching equipment for testing apparatus	324/540	324/542; 324/66; 324/73.1	324/540; 324/73.1
106	X	US 4392107 A	19830705		High voltage insulation testing system	324/73.1		324/73.1
107	X	US 4338561 A	19820706		Method and apparatus for supervising a digital protective relaying system	323/208	324/551; 363/37	324/551
108	X	US 4276605 A	19810630		Universal self-diagnosing appliance control	700/294	324/511; 361/86; 702/60	324/511
109	X	US 4275464 A	19810623		Apparatus and method for calibrated testing of a vehicle electrical system	714/46	68/12.01; 700/210; 700/81; 714/735	714/46
110	X	US 4207611 A	19800610			701/33	324/503; 324/73.1; 701/102; 701/3; 701/45	324/73.1

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		US 4207610 E	19800610		Apparatus and method for testing and controlling manufacture of a vehicle electrical system	701/35	324/503; 324/73.1; 701/102; 701/3; 701/45	324/73.1
111	X	US 4204154 A	19800520		Portable device for use in starting aircraft and having cable lead testing capability	324/538	324/538; 324/539	324/538; 324/539
112	X	US 4180302 A	19791225		Connector plug for vehicle electrical tester	439/607	324/503; 324/538; 439/668; 439/912	324/538
113	X	US 4140964 A	19790220		High voltage breakdown test circuit for insulation testing utilizing a predetermined fixed amount of energy	324/551		324/551
114	X	US 4130794 A	19781219		Methods and means for identifying and testing circuit connections	324/538	324/66; 379/25	324/538
115	X	US 4130794 A	19781219					

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116	X	US A	4096539	19780620	Detector of backfeed electrical currents	361/93.6	324/500; 324/539; 361/54; 361/87	324/539
117	X	US A	3873818	19750325	ELECTRONIC TESTER FOR TESTING DEVICES HAVING A HIGH CIRCUIT DENSITY	714/724	714/738	714/724
118	X	US A	3763425	19731002	METHOD OF TESTING THE CONTINUITY OF AN ELECTRICAL CONDUCTOR BY USE OF AN ELECTRON BEAM CONVERTED FROM HIGH TO LOW ENERGY	324/501	250/310; 250/492.1 ; 324/538; 324/751	324/538
119	X	US A	3638108	19720125	METHOD OF TESTING AN AUTOMOBILE BATTERY AND ELECTRICAL SYSTEM WHILE IN CIRCUIT, USING A BOOSTER BATTERY	324/433	324/429; 324/551; 73/118.1	324/551